


<b>Search Notes</b>  	<b>Application/Control No.</b>  10521173	<b>Applicant(s)/Patent Under Reexamination</b>  OKUYAMA ET AL.
	<b>Examiner</b>  ANDREW P BAINBRIDGE	<b>Art Unit</b>  4156

SEARCHED			
Class	Subclass	Date	Examiner
222	192	3/31/08	APB

SEARCH NOTES		
Search Notes	Date	Examiner
Reviewed all IDS	3/31/08	APB
Angstrom and Nanometer	3/28/08	APB
Soft X Ray	3/28/08	APB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner